

Quantum transport in exfoliated graphene on ultrathin crystalline  $\beta$ -Si<sub>3</sub>N<sub>4</sub>

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We present the first experimental report on the transport properties of graphene devices on ultrathin-Si<sub>3</sub>N<sub>4</sub>. Our study provides a quantitative understanding of the physics of ultrathin Si<sub>3</sub>N<sub>4</sub> as a gate for graphene-based devices. The Si<sub>3</sub>N<sub>4</sub> ultrathin film was grown on Si(111) under UHV conditions and investigated by scanning tunneling microscopy (STM). Subsequently, an exfoliated graphene flake was deposited on top of it by a PMMA-based transfer technique. A Hall bar device was fabricated from the graphene flake. STM was again employed under UHV conditions to study the graphene flake after device processing, showing that its surface quality is preserved. Back gate modulation of the carrier type and density in the graphene channel, weak localization, and tunneling across the dielectric are observed in magneto-transport measurements at 4.2 K. Experimental data of tunnel current due to back gate modulation as a function of temperature is discussed in terms of the Poole-Frenkel and Fowler-Nordheim mechanisms.

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